

On the Representativity of Electrode Microstructure Parameters and Their Electrochemical Response for Lithium Ion Batteries (A02-0443)

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2. Computational Science Center, National Renewable Energy Laboratory, Golden, Colorado 80401, USA Representativity analysis is essential Why does representativity analysis matter ? RVE analysis enables model to be predictive. RVE analysis provides imaging requirements for FOV Is this volume representative ? What imaging technique Representativity analysis must be carefully defined should I use to achieve RVE is aspect ratio dependent. For electrodes: representative section area (RSA) x electrode thickness. RVE is property-specific: $\rm RVE = max(\rm RVE_p)$... and representative of what ? representativity ? and for which use case ? considering all properties *p* relevant for the model. RVE is **field of view (FOV) dependent**. RVE convergence with FOV must be Representativity determined to conclude on representativity, otherwise: risk of underestimation. \cdot Microstructure representativity ≠ performance representativity predictive model Error/representativity propagation from microstructure parameters to (representativity electrochemical performances. eRVE are increasing with C-rate: larger volumes are required to model electrodes at fast charge rate. analysis For C-rate ≤2.5, 154x144 µm² is large enough to verify electrochemical error analysis) performances representativity with a 5% threshold. For higher charge 10 µm Otherwise, only qualitative results rates, RVE analysis is not conclusive as FOV is not large enough to Anode (graphite) Electrolyte Cathode (NMC532) confirm convergence How to calculate Representative Volume Element (RVE) size ? \sqrt{RSA} for a 5% representativity threshold (RVE is aspect athode (AR: cst thickness) anode (AR: cst thickness) anode (AR: 1:1:1) Definition ratio-dependent, Repeat for different $\text{if } p(V_i) \approx p(V_j) \forall i \neq j$ 5% threshold property-specific, (m77 $\Omega = \Omega_{V_i} = \Omega_{V_i}$ Same size Ω subvolume Repeat for 40 and FOVand size different FOV with **NNC** $V_i \cap V_j = \emptyset$ Independent volumes RVE=40.7um³ dependent 30 RSA= then Ω is a representative volume for property p: RVE analysis can be -30.9um $RVE_p = \Omega$ 40 abor 20 automated with NREL Volume V_i of size Ω_{V_i} is Microstructure Analysis 8 For For Toolbox (MATBOX, How to cut subvolumes V ? representative of the property p, if For tortuosity factor 11.5% rel. std. de Usseglio et al, SoftwareX, 2022) p calculated on other independent 40 For batteries: we are looking for the nce RVE has be Subvolume cubit root (µm) volumes V_i of same size is similar representative section area (RSA). 100 150 200 FOV section area square root (μ m) ulate $p(V_i)$ on n subvolumes, and calculate relative standard deviation to check $p(V_i) \approx p(V_j)$ **Dynamic electrochemical RVE (eRVE)** Error propagation: x% error on microstructure parameter is not x% error Perform r on electrochemical performances, and likewise for representativity threshold. 6C 6C 6C 0-10 0.3 0.5 0.6 tion Graphite 0.7 0.30 100 $\frac{1}{1}\sum_{i=1}^{n} |\langle C_{e,k}(x_i, t_i)\rangle - \langle \langle C_e(x_i, t_i)\rangle\rangle|^2$ -Θ- S_{r mea} For instance, electrolyte eRVE can be calculated for $S_r(x_i, t_i) =$ 1C concentration relative std a variety of metrics: e.g.: -4C between independent anode intercalation fraction -60 Repeat for different 16 subvolumes can be reached at cell voltage limit 20 subvolume calculated, and then or lithium plating subvolumes sizes compared with microstructure parameter ----O representativity Calculate standard deviation ong cell thickness (um) Section area $x \times x \mu m^2$, $x (\mu m)$ Static RVE and dynamic eRVE comparison and representativity propagation For a 5% representativity threshold (some values are underestimated due to Representative section area $x imes x \mu m^2$, $x (\mu m)$



st do n cell voltage or lithium plating, what should be the %std for microstructure parameters" (y-axis) for a given C-rate (x-axis) ? For low C-rate (52.5), a higher threshold

Propagation analysis: for a 5%

- can be used: (52-5), a figure unestion can be used: (52-5), a figure unesting microstructure parameters for both electrodes induce lower relative deviations in cell voltage and plating onset.
- For intermediate charge rate (2.5503.5) relative deviations in microstructure parameters for the NMC still induce lower relative deviations in cell voltage and plating onset, while for the graphite they induce higher deviations. For higher charge rate (23.5-40), relative deviations in microstructure parameters for both electrodes induce larger relative deviations in cell voltage and plating onset.

entation, characterization, visualization, correlation, and meshing, SoftwareX, 2022

E. L. E. Usseglio-Viretta, A. M. Colclasure, J. M. Allen, D. P. Finegan, P. Graf, and K. Smith, Microstructure Scale Lithium-ion Battery Modeling, Part II: on the representativity of microstructure parameters and electrochemical response, in reduction This work was authored by the National Renewable Energy Laboratory, operated by Alliance for Sustainable Energy, LLC, for the U.S. Department of Energy (DOE) under Contract No. DE-AC36-08GO28308. Funding provided by the U.S. Department of Energy Office of Energy Efficiency and Renewable Energy, Vehicle Technology Office, eXtreme Fast Charge and Cell Evaluation of Lithium-ion Batteries (XCEL) Program, program manager Samuel Gillard. This research was performed using computational resources sponsored by the U.S. Department of Energy Efficiency and Renewable Energy Laboratory. The views expressed in the article do not necessarily represent the views of the DOE or the U.S. Government. The U.S. Government retains and the publisher, by accepting the article for publication, acknowledges that the U.S. Government retains a nonexclusive, paid-up, irrevocable, worldwide license to publish or reproduce the published form of this work, or allow others to do so, for U.S. Government purposes.

L. E. Usseglio-Viretta, P. patel, E. Bernhardt, A. Mistry, P. P. Mukherjee, J. Allen, S. J. Cooper, J. Laurencin, and K. Smith, MATBOX: An Open-source Microstructure Analysis Toolbox for microstructure generation, segn

245th Electrochemical Society Meeting Marriott Marquis – San Francisco, California May 26-30, 2024 NREL/PO-5700-89968